

CIL
 EMU CRITICAL ITEMS LIST

12/24/91 SUPERSEDES DB/31/90

ANALYST:

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NAME P/N QTY	CRIT	FAILURE MODE & CAUSES	FAILURE EFFECTS	RATIONALE FOR ACCEPTANCE
CAUTION AND WARNING SYSTEM, ITEM 15B SV785970-13 (1)	2/2	15BPHOB: Failure of one or more read/write memory locations. CAUSE: Electronic component failure.	END ITEM: Erroneous processing of CMS data. OIE INTERFACE: Activation of OIE indicator on BCM and warning tone. All CMS data suspect. MISSION: Terminate EVA. Loss of URS of one EMU. CREW/VEHICLE: None.	A. Design - Established reliability capacitors and resistors are qualified to the requirements of applicable military specification and thermal shocked per Condition B Test Method 107 of MIL-STD-202. Microcircuits are qualified to the requirements of MIL-M-38510 and receive the burn-in of Class B parts per method 3004 of MIL-STD-883. Transistors, diodes are qualified to the requirements of MIL-S-19500 and receive the burn-in of JANIKV level parts per the applicable methods, 103B, 1039, 1040 or MIL-STD-750. The electronic components are operating within the power dissipating requirements of SMS 2804. The printed circuit (PC) boards are fiberglass/epoxy per MIL-P-13069 type 0F and manufactured in accordance with NSPC-STD-154. Parts mounting and soldering is per NSPC-STD-156 and MHS300.4 (31-1). The CMS is a mother/daughter board assembly. The daughter boards are held in place by metal card guides which also provide thermal transfer from the board heatinks to the EMU case. The top cover of the CMS exerts a downward force on the daughter boards to keep them properly seated in the mother board connectors. Flex Tape (Kapton insulated, flexible flat conductor) instead of conventional Teflon coated wires is used to provide connections between the mother board and the external connectors. This prevents pinching of the conductor during item assembly. The PC board assemblies are conformal coated per MIL-N-46166 (Dow Corning RTV 3140) for environmental and humidity protection. Electrical connectors are environmentally sealed to prevent damage due to contamination and humidity. B. Test - Component Acceptance Test - Full functioning of the CMS is verified during Item AIP Tests including continuity, logic flow, N-state sequencing, fault simulation, verification of status and fault messages, warning and alert tones activation, and OIE activation. These tests are conducted upon completion of random vibration testing. PDA Test - The above electrical tests are repeated during PLSS PDA to

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ANALYSIS:

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	2/2	LSOFR08:		<p>verify CNS operation. The CNS is also operational during other PLSS PDA electrical tests such as sensor accuracy checks, Item 123 fan operation, Item 174 RIDE checkout, and solenoid valve actuation.</p> <p>Certification - The item completed the 15 year structural vibration and shock certification requirement during 10/83. It's 42806-244 (add jumper wires, add diode CR22), change resistor R501), 42806-345-3 (eliminate interferences with P199), 42806-718 (overstressed resistor R309 due to delta data logger, software change, diode VR201 rewiring), 42846-942 and 42806-942-7 (transistor Q201 lead stress relief), have been incorporated and certified by similarity or analysis since this configuration was tested.</p> <p>C. Inspection - Each circuit board, the flex tape, and connectors are inspected for damage and contamination prior to being placed into finished stores. The CNS assembly is inspected internally and externally for damage and contamination during item assembly and externally during ATP. All soldering is inspected by HS DA and DCAB QA per NMS1500.4 (3R-1).</p> <p>D. Failure History - R-EMU-950-0007 (B-2-B3) WUWHM was not retained after a 10 second power interruption during in-process testing. The cause was found to be inadvertent resetting and reactivation of the microprocessor during the power off state due to capacitor discharging. Change 42804-244-1 was issued to change one resistor and add a diode to keep the microprocessor off.</p> <p>E. Ground Burnaround - Tested per #EMU-R-001, DCN bite light verification.</p> <p>F. Operational Use - Crew Response - PreEVA: trouble shoot problem using RTDS, if no success, consider EMU 3 if available. EMU no go for EVA.</p>

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NAME P/N QTY	CRIT	FAILURE MODE & CAUSES	FAILURE EFFECT	RATIONALE FOR ACCEPTANCE
	2/2	150FM08:		

EVA: When CVS issues BITE indication and R108 confirms invalid EMU BITE data, terminate EVA.
 Training - Standard EMU training covers this failure mode.
 Operational Considerations - flight rules define operational CVS as at least able to monitor a valid status list. EVA checklist procedures verify hardware integrity and system operational status prior to EVA. Real Time Data System allows ground monitoring of EMU systems.